

Cantilever-based Near-field Scanning Optical Microscope Sensor NSOM-50/100/WAP

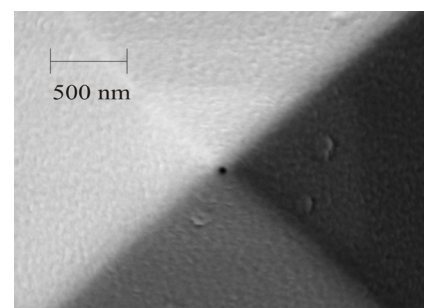
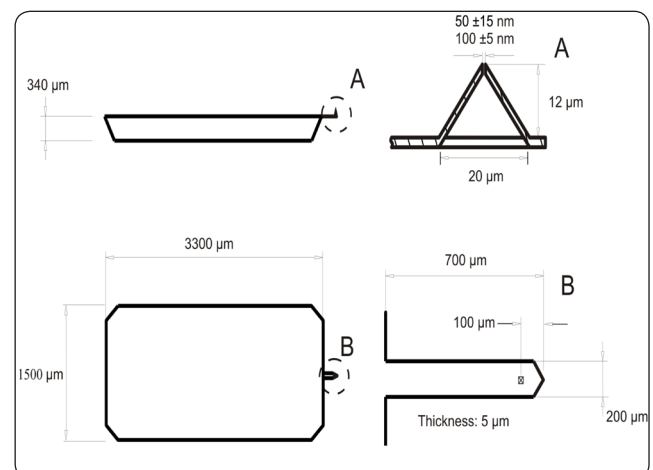
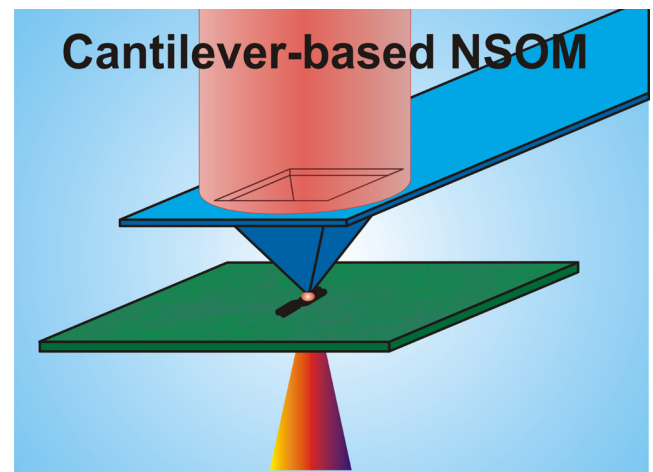
NMI-TT's silicon NSOM sensors have helped to open up new areas of research by overcoming some of the limitations associated with traditional fiber NSOM probes.

Our cantilever-based silicon sensors utilizes a hollow, aluminum-coated, pyramidal tip with a small aperture at the apex to focus the NSOM beam.

This design yields an increase in light transmission by two orders of magnitude over that of a traditional fiber probe.

Offered with apertures of 50nm, 100nm, or apertureless, they are suited for various NSOM applications in industry, nanobiology, neuroscience, and genetic engineering.

In addition, NMI-TT's NSOM probes enable topographical AFM measurements and offer AFM/SPM users the ability to incorporate NSOM measurement into their current systems, without the addition of expensive hardware.



Technical Data	Typical Value	Range Comment
Force Constant	3 N/m	1.5 - 6 N/m
Resonance Frequency	20 kHz	14 - 22 kHz
Length	700 μm	680 - 720 μm
Mean Width	200 μm	195 - 205 μm
Thickness	5 μm	4 - 6 μm
Tip Height	13 μm	12 - 14 μm
Aperture Size (50)	50 nm	35 - 65 nm
Aperture Size (100)	100 nm	95 - 105 nm
Aperture Size (WAP)	Without Aperture	
Tip Style	Pyramidal	
Coating	Aluminium (tip side)	

NSOM-50/100/WAP

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